# The effect of dopants on the microwave dielectric properties of $Ba(Mg_{0.33}Ta_{0.67})O_3$ ceramics

Kuzhichalil P. Surendran and Mailadil T. Sebastian<sup>a)</sup> Materials and Minerals Division, Regional Research Laboratory, Trivandrum-695 019, India

Pezholil Mohanan

Department of Electronics, Cochin University of Science & Technology, Kochi-686 022, India

Mohan V. Jacob

School of Engineering, James Cook University, QLD 4811, Australia

(Received 4 November 2004; accepted 22 August 2005; published online 15 November 2005)

The effect of dopants with different valencies and ionic radii on the densification, structural ordering, and microwave dielectric properties of  $Ba(Mg_{1/3}Ta_{2/3})O_3$  (BMT) is investigated. It is found that dopants such as  $Sb_2O_5$ , MnO, ZrO<sub>2</sub>, WO<sub>3</sub>, and ZnO improve the microwave dielectric properties of BMT. Addition of trivalent dopants is detrimental to the cation ordering and dielectric properties of BMT. A correlation between the microwave dielectric properties of BMT and ionic radii of the dopant has been established. The variation of the dielectric properties of pure and doped BMT at cryogenic temperatures is also discussed. © 2005 American Institute of Physics. [DOI: 10.1063/1.2127124]

# I. INTRODUCTION

Dielectric resonators have achieved an important position, as the key element in microwave filters, antennas, and oscillators. The discovery<sup>1</sup> of the low loss complex perovskite  $Ba(Mg_{1/3}Ta_{2/3})O_3$  (BMT) has turned out to be a breakthrough in the research on microwave dielectrics, since it has the highest quality factor reported until date. However, the sintering conditions for obtaining high performance BMT ceramic is very stringent because of its poor sinterability (sintering temperature is higher than 1600 °C), which is thought to be due to the formation of some satellite secondary phases in the calcined powders. Solution chemistry offers alternative approaches such as sol-gel technique for synthesis of BMT powders.<sup>2</sup> But the chemical synthesis of BMT was not the most appropriate method for industrial production due to the complexity of the procedures involved, high cost of production, and comparatively poor microwave dielectric properties.<sup>2</sup>

In a significant study, Nomura<sup>3</sup> found that doping of BMT with 1 mol % of Mn not only promotes sinterability by lowering the sintering temperature but also increases the unloaded Q value appreciably. Later on Matsumoto *et al.*<sup>4</sup> studied doping effects of SnO<sub>2</sub> in BMT, which too yielded excellent microwave dielectric properties. Their study revealed that on addition of 10–15 mol % of BaSnO<sub>3</sub> into BMT ceramics increased the Q value up to 33 000 at 10 GHz and the  $\tau_f$  approached negative values. In another report<sup>5</sup> Yoon *et al.* added hexavalent WO<sub>3</sub> in the form of BaWO<sub>4</sub> and found that the addition of barium tungstate up to 5 mol % increased the lattice constant ratio (*c/a*), order parameter, density, and dielectric quality factor due to the substitution of Ta<sup>5+</sup> by W<sup>6+</sup> at above 1430 °C. The effect of nickel on the microwave

dielectric properties of BMT has also been studied.<sup>6</sup> It was found that the dielectric properties such as  $\varepsilon_r$  and  $\tau_f$  were slightly increased with the substitution of Ni<sup>2+</sup> ion at Mg<sup>2+</sup> site in Ba(Mg<sub>1/3</sub>Ta<sub>2/3</sub>)O<sub>3</sub>, but the quality factor was decreased. The effects of low melting additives<sup>7</sup> such as NaF reduced the processing temperature of BMT but the formation of secondary phases such as Na<sub>3</sub>TaO<sub>4</sub> should be suppressed to achieve stable high Q phase. Chai *et al.*<sup>8</sup> and Chai and Davies<sup>9</sup> reported that with the addition of tetravalent ions, the 1:2 ordering of B-site cations in complex perovskite Ba(Mg<sub>1/3</sub>Ta<sub>2/3</sub>)O<sub>3</sub> ceramics was transformed into 1:1 ordering with partial substitution of Zr<sup>4+</sup>, Ce<sup>4+</sup>, and Sn<sup>4+</sup> to the  $(Mg_{1/3}Ta_{2/3})^{4+}$  site. However, the above report provided no information as to how the microwave dielectric properties of BMT vary with *B*-site substitution. Shirey<sup>10</sup> reported that the quality factor deteriorated with Ga addition in BMT, nevertheless a reduction in sintering temperature. The densification and quality factor of low loss BMT were also reported<sup>11</sup> to be improved with the addition of Y<sub>2</sub>O<sub>3</sub>. Another recent study<sup>12</sup> suggested that the addition of pentavalent dopant such as V<sub>2</sub>O<sub>5</sub> did not significantly affect the temperature coefficient of resonant frequency but it improved the microwave quality factor consequent to the substitution of  $V^{5+}$  in the Ta<sup>5+</sup> site. Recently Surendran *et al.*<sup>13</sup> reported that the addition of suitable glasses reduce the sintering temperature and improve the quality factor of BMT. It has also been reported<sup>14</sup> that a slight nonstoichiometry of Mg or Ba can improve the density, order parameter, and thereby the quality factor.

Hence from a brief literature survey made above, it is clear that even though BMT ceramic possess the highest Qfactor in literature, a comprehensive effort is needed to correlate the complex relationship between the structure and low loss nature of BMT. A number of parameters starting from the synthesizing stage, up to the final high-temperature

<sup>&</sup>lt;sup>a)</sup>Author to whom correspondence should be addressed; electronic mail: mailadils@yahoo.com

densification have to be controlled to achieve high Q phase in BMT ceramics.<sup>15</sup> The origin and purity of the initial raw materials also have a considerable influence on the sinterability. Though many research groups have studied the effect of various additives on the microwave dielectric properties and sinterability of BMT, the doping was performed under different conditions: sometimes before calcination and sometimes after. Hence the reported Q values show a wide scatter, which may be due to the different measuring techniques used and variations in the synthesizing conditions. To overcome this difficulty, we carried out a comprehensive investigation in which aliovalent and isovalent additives were added to the calcined BMT under similar conditions in a systematic way. The aim of this study was to investigate the effect of various dopants of different ionic radii and valency on the densification, sinterability, and dielectric properties of BMT. The complex relationship between dielectric loss and the orderdisorder transformation on the B-site cations in BMT ceramic materials is also presented in this paper.

# **II. EXPERIMENT**

# A. Synthesis

The Ba(Mg<sub>1/3</sub>Ta<sub>2/3</sub>)O<sub>3</sub> precursor was prepared by the conventional solid-state ceramic technique. High-purity (>99.9%) powders of BaCO<sub>3</sub> (Aldrich Chemicals),  $(MgCO_3)_4Mg(OH)_2 \cdot 5H_2O$  (Aldrich Chemicals), and  $Ta_2O_5$ (Nuclear Fuel Complex, Hyderabad) were used as the starting materials. The chemicals were weighed according to the stoichiometric compositions and were ball milled in deionized water for 24 h. The slurry was dried in an oven at 100 °C and calcined in a platinum crucible at 1200 °C for 10 h with intermediate grinding. The calcined BMT precursor was divided into several batches and different mol % of divalent (MnO, NiO, ZnO, and Co<sub>3</sub>O<sub>4</sub>), trivalent (Al<sub>2</sub>O<sub>3</sub>, Ga<sub>2</sub>O<sub>3</sub>, Fe<sub>2</sub>O<sub>3</sub>, In<sub>2</sub>O<sub>3</sub>, Nd<sub>2</sub>O<sub>3</sub>, and Bi<sub>2</sub>O<sub>3</sub>), tetravalent (TiO<sub>2</sub>,  $SnO_2$ ,  $ZrO_2$ ,  $CeO_{2-\delta}$ , and  $HfO_2$ ), pentavalent (V<sub>2</sub>O<sub>5</sub>, Sb<sub>2</sub>O<sub>3</sub>, and  $Nb_2O_5$ ), and hexavalent (WO<sub>3</sub> and MoO<sub>3</sub>) dopants were added to the calcined BMT. The calcined powder was then ground thoroughly for several hours and 3 wt % aqueous solution of polyvinyl alcohol (PVA) was added to it as a binder. The powder was uniaxially pressed into cylindrical compacts of 14 mm diameter and 6-8 mm thickness under a pressure of 150 MPa in a tungsten carbide die. These compacts were fired at a rate of 5 °C/min up to 600 °C and soaked at 600 °C for 1 h to expel the binder before they were sintered at 1625 °C for 4 h in air at a heating rate of 10 °C/h. The sintered samples were then cooled to 800 °C at a slow rate of 60 °C/h. The well-sintered samples were annealed at 1450 °C for 40 h to relieve the lattice strain and to enhance cation ordering mechanism. The polished ceramic pellets with an aspect ratio (diameter to height) of 1.8–2.2, which is ideal for maximum separation of the modes, were used for microwave measurements.

# **B.** Characterization

The bulk density of the sintered samples were measured using Archimedes method. The powdered samples were used for analyzing the x-ray diffraction patterns using Cu  $K\alpha$  radiation (Philips x-ray diffractometer). The cell parameters reported in this paper have been derived from powderdiffraction data of all the diffraction lines in the range  $2\theta = 5^{\circ} - 70^{\circ}$  and then taking the weighted average. The possible error in the measurement of lattice parameters is in the range of ±0.000 05 which was calculated using the method of least squares. The cation order parameter for BMT was calculated using the following equation:

$$S = \sqrt{\frac{(I_{(100)}/I_{(110),(102)})_{\text{observed}}}{(I_{(100)}/I_{(110),(102)})_{\text{theoretical}}}},$$
(1)

where the theoretical value of the ratio of the integral intensity of super structural reflection line (100) to that of (110,102) line,  $(I_{100}/I_{110,102})_{\text{theoretical}}$  is 8.3% putting all the atoms in approximate ideal positions in BMT crystal lattice. In real case where the structure factors of major reflections (which is a function of ions located in crystal structure) can vary slightly with dopant substitutions. The recent structural analysis carried out by Janaswamy *et al.*<sup>16</sup> and Lufaso<sup>17</sup> suggest that a more accurate value for  $(I_{100}/I_{110,102})_{\text{theoretical}}$  is equal to 8.7%. This value has been used in the present calculation. The error in the calculation of the order parameter was less than ±0.001.

The dielectric properties of the materials were measured in the microwave frequency range using a fully automated vector network analyzer HP 8510C (Hewlett-Packard, Palo Alto, CA). The dielectric constant  $\varepsilon_r$  was measured by Hakki and Coleman<sup>18</sup> method and the samples were end shorted with finely polished copper plates coated with gold. The microwave is coupled though E-field probes as described by Courtney.<sup>19</sup> The accuracy of  $\varepsilon_r$  measurement is restricted to the accuracy in measurement of resonant frequency and dimensions of the sample. The error in  $\varepsilon_r$  measurement was typically less than ±0.01. Usually, three samples were prepared in a batch and the measurements were made at least twice per each specimen. The unloaded quality factor  $Q_u$  of the resonance was determined using a copper cavity whose interior was coated with silver and the ceramic dielectric is placed on a low loss quartz spacer, which reduces effect of losses due to the surface resistivity of the cavity. The coefficient of thermal variation of resonant frequency  $(\tau_f)$  was measured by noting the temperature variation of the resonant frequency of TE<sub>011</sub> mode in the reflection configuration over a range of temperature 20-80 °C when the sample was kept in the end shorted position.

The measurement system used for microwave characterization of the samples at cryogenic temperature consists of network analyzer (HP 8722 C), closed cycle refrigerator (APD DE-204), temperature controller (LTC-10), vacuum dewar, a personal computer, and a TE<sub>01δ</sub> mode post dielectric resonator. The resonator loaded with the sample was cooled from room temperature to approximately 17 K. Using the network analyzer the TE<sub>01δ</sub> mode is identified. The  $S_{21}$ ,  $S_{11}$ , and  $S_{22}$  parameter data sets around the resonance were measured at a temperature of 17 K. The transmission mode Q-factor (TMQF) technique<sup>20</sup> has been used to process the data and to estimate the coupling coefficients ( $k_1$  and  $k_2$ ) and the unloaded Q factor. For higher temperatures only  $S_{21}$  was



FIG. 1. Powder-diffraction pattern of BMT doped with 5 mol % of the additives. (\*) superstructural reflections, (Pure) BMT undoped and (unannealed), (Anneled) BMT undoped and annealed at 1450/40h, (1) Ba<sub>3</sub>NiTa<sub>2</sub>O<sub>9</sub>, (2) Ba<sub>4</sub>Ta<sub>2</sub>O<sub>9</sub>, (3) BaCoO<sub>2.93</sub>, (4) Ba<sub>10</sub>Al<sub>2</sub>O<sub>13</sub>, (5) BaGa<sub>12</sub>O<sub>19</sub>, (6) Fe<sub>4</sub>Ta<sub>2</sub>O<sub>9</sub>, (7) InTaO<sub>4</sub>, (8) Nd<sub>2</sub>O<sub>3</sub>, (9) Bi<sub>2</sub>O<sub>3</sub>, (10) BaBiO<sub>3</sub>, (11) BaCeO<sub>3</sub>, (12) BaTiO<sub>3</sub>, (13) BaSnO<sub>3</sub>, (14) Ba<sub>2</sub>HfO<sub>4</sub>, (15) BaZrO<sub>3</sub>, (16) BaV<sub>3</sub>O<sub>8</sub>, (17) VTaO<sub>4</sub>, (18) BaWO<sub>4</sub>, and (19) BaMoO<sub>4</sub>.

measured and the unloaded Q factor was calculated using a simplified TMQF method.<sup>21</sup> The simplified TMQF method calculates the coupling coefficient of both ports at each measurement temperature and hence the accurate unloaded Q factor. The perpendicular component of the real part of relative permittivity and loss tangent is calculated from the resonant frequency and unloaded Q factor, respectively.

## **III. RESULTS AND DISCUSSION**

# A. XRD analysis

The dopants used in this investigation are classified as a function of their stable oxidation states as divalent, trivalent, tetravalent, pentavalent, and hexavalent. Aliovalency and comparable ionic size with *B*-site cations are taken as the basic criterion for selecting dopants in this study. The x-ray diffraction (XRD) patterns of an unannealed pure ceramic sintered at 1625 °C and a sample annealed at 1450 °C for

40 h are given in Fig. 1. The superstructure reflections are clearly seen in the powder-diffraction pattern recorded from the annealed specimen. This observation is attributed to the existence of small 1:2 ordering domains, which grow at higher temperatures on annealing. The XRD patterns of BMT doped with 5 mol % of different dopants are also given in Fig. 1. When an additive is added to BMT, the following phenomena are possible to happen: (a) the dopant ion may partially substitute for A or B site in BMT, (b) the additive melts and may aid in liquid phase sintering, and (c) the additive reacts with the matrix and forms secondary phase with it. Owing to the limitations of XRD as a comprehensive tool for structural analysis, the possibility of trivalent ion substituting at any of the B site in BMT could not be explored, but it is reasonable to expect that bigger trivalent dopant ions such as Nd and Bi can go into the A site to form a structure  $Ba_{1-3x}(Nd/Bi)_{2x}(Mg_{1/3}Ta_{2/3})O_3$ . Of the trivalent additives we have used in this investigation, the only additives which

Downloaded 16 Nov 2005 to 210.212.236.73. Redistribution subject to AIP license or copyright, see http://jap.aip.org/jap/copyright.jsp

TABLE I. Unit-cell properties and densification of pure and doped BMT. The standard deviation in the determination of lattice parameters a and c are  $\pm 0.00005$ .

BMT + dopant	Mol % of dopant	c/a	Cell volume (Å) <sup>3</sup>	X-ray density (g/cm <sup>3</sup> )	Percentage densification	Order parameter
Pure	0	1.2243	205.499	7.625	93.0	0.818
MnO	0.1	1.2251	205.213	7.636	95.9	0.902
NiO	0.1	1.2243	205.526	7.624	95.6	0.833
ZnO	0.5	1.2248	205.556	7.623	97.1	0.898
$Co_3O_4$	1.0	1.2239	205.606	7.621	94.1	0.459
$Al_2O_3$	0.1	1.2248	205.068	7.641	93.3	0.686
$Ga_2O_3$	0.1	1.2244	205.531	7.624	93.5	0.889
Fe <sub>2</sub> O <sub>3</sub>	0.1	1.2246	205.004	7.643	95.5	0.795
$In_2O_3$	0.1	1.2244	205.530	7.624	95.3	0.615
$Nd_2O_3$	0.1	1.2233	205.336	7.631	95.1	0.86
Bi <sub>2</sub> O <sub>3</sub>	0.1	1.2237	205.082	7.640	98.1	0.647
TiO <sub>2</sub>	0.1	1.2244	205.579	7.622	97.6	0.386
$SnO_2$	0.5	1.2247	205.161	7.638	97.9	0.825
$HfO_2$	0.1	1.2227	205.449	7.627	98.3	0.467
$ZrO_2$	0.5	1.2240	206.229	7.598	97.1	0.500
$CeO_{2-\delta}$	0.5	1.2234	204.949	7.645	94.1	0.825
$V_2O_5$	0.1	1.2238	205.021	7.642	93.4	0.730
$Sb_2O_3$	0.1	1.2252	204.833	7.650	95.1	0.881
$Nb_2O_5$	0.1	1.2233	205.336	7.631	94.2	0.759
WO <sub>3</sub>	0.5	1.2249	204.949	7.646	96.7	0.892
$MoO_3$	0.5	1.2232	205.367	7.630	97.5	0.462

have the ionic radii close to 1 Å are Nd<sup>3+</sup> (0.983 Å) (Ref. 23) and Bi<sub>2</sub>O<sub>3</sub> (1.03 Å) which are likely to substitute the Ba site in Ba(Mg<sub>1/3</sub>Ta<sub>2/3</sub>)O<sub>3</sub>. In a previous report,<sup>22</sup> a bigger trivalent ion such as La<sup>3+</sup> doped in BMT results in the formation of a 1:1 ordered structure coexisting with 1:2 ordered phase. It is evident that the addition of trivalent Bi<sub>2</sub>O<sub>3</sub> severely damages the cation ordering arrangement of BMT on higher concentration of the dopant as there are hardly any superstructure reflections in the XRD pattern [Fig. 1 (Bi)].

The XRD pattern of BMT doped with 5 mol % of Sb<sub>2</sub>O<sub>3</sub> is given in Fig. 1 (Sb). It is well known that at high temperatures, the oxidation state of Sb will change to 5, which may partially replace the Ta site in BMT. Here the XRD pattern is well ordered and no trace of any additional peak is visible in the XRD spectrum, which is reflected in the excellent microwave dielectric properties of BMT ceramics doped with  $Sb_2O_3$ . In the case of  $Sb_2O_3$  doping, the size difference<sup>23</sup> between partially substituted Sb<sup>5+</sup> ion (0.6 Å) in the Ta<sup>5+</sup> site with  $Mg^{2+}$  ion (0.72 Å) is 0.12 which effectively promotes the cation ordering. The doping with Nb<sub>2</sub>O<sub>5</sub> also does not form any secondary phase with BMT [Fig. 1 (Nb)] which is understood since Nb5+ has an ionic radius same as that of Ta<sup>5+</sup> (0.64 Å).<sup>23</sup> Kim et al.<sup>24</sup> found that WO<sub>3</sub> doping enhances the 1:2 ordering of BMT due to the greater difference in charge and ionic radius between W<sup>6+</sup> and Ta<sup>5+</sup> ions when the latter substitutes at the Ta site. In the present study it was revealed that the influence of hexavalent dopants enhanced the B-site cation ordering in complex perovskite Ba(Mg<sub>1/3</sub>Ta<sub>2/3</sub>)O<sub>3</sub> due to obvious reasons of increased charge difference between the additive cation and divalent Mg in the B'-site of BMT.

## **B.** Densification

The percentage densification and unit-cell properties of doped BMT which corresponds to the best of their microwave dielectric properties for each dopant are given in Table I. The densification is comparatively larger for ZnO. But the addition of dopants in large amount have a detrimental effect on densification as it may breed grain growth. The densification is very poor for Al<sub>2</sub>O<sub>3</sub> doped samples, which is attributed to the formation of barium aluminate [see Fig. 1 (Al)]. Apart from Nd<sup>3+</sup> and Bi<sup>3+</sup> ions, all other dopants in this family probably may substitute only at the B site of the complex perovskite. It is interesting to note from Table I that the densification behavior of Bi2O3 dopant in BMT is best among the trivalent dopants we used in this study, which is believed to be due to liquid phase sintering. Nevertheless, it could not lead to any improvement in the dielectric properties of BMT ceramics as shown later. With exception of  $CeO_{2-\delta}$  the tetravalent additives perform fairly well (>97%) of their theoretical density) in densifying the BMT (see Table I). On addition of more than 0.5 mol % of the dopant, the density decreases, due to obvious reasons of formation of secondary phase  $BaMO_3$  (M=Ti, Sn, Zr, Ce, and Hf) as evidenced by the XRD analysis given in Fig. 1. The densification behavior of Sb<sub>2</sub>O<sub>3</sub> is good among pentavalent additives, whose cation is likely to replace Ta<sup>5+</sup> in BMT. On the other hand, the doping with V2O5 does not improve the density as it resulted in the formation of secondary phases such as  $BaV_3O_8$  and  $VTaO_4$  [see Fig. 1 (V)]. This result is contradictory to a recent observation made by Huang et al.<sup>12</sup> who observed an increase in the density and dielectric properties of BMT with V2O5 addition for obvious reasons of liquid

phase sintering and partial substitution of  $V^{5+}$  at the Ta<sup>5+</sup> site. There is a marginal improvement in density for BMT doped with small amount of WO<sub>3</sub> and MoO<sub>3</sub>.

# C. Cation ordering

The properties of the unit cell of undoped and doped BMT are given in Table I. The present investigation revealed that for pure ordered complex perovskite BMT sintered at 1625 °C assuming a trigonal superstructure, the unit-cell parameters are a=5.7807(2) Å and c=7.0840(1) Å. The x-ray density of pure BMT=7.625 g/cm<sup>3</sup>, assuming the molecular weight to be 314.596 g.<sup>25</sup> In the ordered state, the unit cell of BMT expands along the  $\langle 111 \rangle$  direction so that  $c/a \ge \sqrt{(3/2)}=1.2247$ . When sintered BMT samples are annealed at 1450 °C for 40 h, the modified cell parameters are a=5.7878(1) Å and c=7.0930(4) Å so that c/a=1.2255. The order parameters of pure unannealed and annealed BMT are 0.755 and 0.818, respectively.

It is well known that the presence of dopants lead to changes in lattice parameters if they go into the lattice site of the matrix. The unit-cell parameters a and c are modified slightly by doping with divalent ion as seen from Table I. A partial substitution of Mg<sup>2+</sup> with Mn<sup>2+</sup> enhances the cation ordering in BMT which is confirmed by the increase in the values of order parameter. Addition of NiO has been detrimental to its cation ordering and dielectric properties due to the formation of secondary phase  $Ba_3Ni_3O_6$ .<sup>26</sup> It must be noted that among all the trivalent dopants we studied in this work, not even a single dopant improved the 1:2 cation arrangement in BMT so that c/a is greater than 1.2247 (see Table I). This observation categorically points out that the trivalent additives are unsuitable for improving the properties of BMT ceramics. The formation of secondary phases may be probably the reason behind the poor ordering of B-site cations in BMT doped with trivalent ions. The cation order parameter of Sn doped ceramic is reasonably good (see Table I) which is due to 1:2 ordering of the trigonal perovskite. In a previous report, Davies<sup>27</sup> found that introduction of a larger dopant such as Ce (0.87 Å) or Zr (0.72 Å) destroys the 1:2 order in BMT and stabilizes a region of 1:1 order when the substitution levels are up to 25 mol %. But in the present study, no 1:1 ordering powder-diffraction peaks are observed since the maximum doping level is only up to 5 mol %. The order parameter of BMT doped with TiO<sub>2</sub> is poor which is reflected in the dielectric properties of these ceramic at microwave frequencies. This may be due to the presence of secondary phase of BaTiO<sub>3</sub> which is a lossy material with high dielectric constant. The cation ordering is only 0.5 when the concentration of the  $ZrO_2$  dopant is 0.5 mol %. On the other hand the cation ordering is poor in HfO<sub>2</sub> doped BMT. It is evident that the doping of Sb<sub>2</sub>O<sub>3</sub> is found to be excellent among the 20 dopants we used in this investigation in terms of the dielectric properties in the microwave frequency region. The doping of  $V_2O_5$  and  $Nb_2O_5$  did not produce any significant contribution towards the ordering. The cation ordering is higher for WO<sub>3</sub> than MoO<sub>3</sub> additions, (see Table I) which could be due to the partial substitution of W at the Ta site in BMT.

#### D. Microwave dielectric properties

#### 1. Divalent dopants

The microwave dielectric properties of pure BMT ceramic samples sintered at 1625 °C for 4 h before annealing are  $\varepsilon_r = 24.3$ ,  $Q_{\mu}xf = 80\ 000$  GHz, and  $\tau_f = 7\ \text{ppm}/^\circ\text{C}$ . On annealing the samples at 1450 °C for 40 h (which has been the optimized condition for annealing), the dielectric properties are  $\varepsilon_r = 24.4$ ,  $Q_{\mu}xf = 100500$  GHz, and  $\tau_f = 8$  ppm/°C. Figure 2(a) shows microwave dielectric properties of BMT ceramics doped with divalent dopants such as MnO, NiO, ZnO, and Co<sub>3</sub>O<sub>4</sub>. The dielectric constant of 0.5 mol % Mn<sup>2+</sup> and Zn<sup>2+</sup> doped BMT samples increase to 26.7 and 25.9, respectively, due to the higher ionic polarizabilities of Mn and Zn ions (2.64 and 2.04, respectively). With higher concentration of the dopant ions, the measured dielectric constant decreases. For Ni and Co additives, the dielectric constant decreases with larger amount of doping which is consistent with previous reports.<sup>28</sup> The temperature coefficient of resonant frequency  $(\tau_f)$  increases with doping for NiO, Co<sub>3</sub>O<sub>4</sub>, and ZnO additives while  $\tau_f$  decreases for MnO addition. The Mn doped BMT samples are showing high quality factor of  $Q_{u}xf = 162\ 800\ \text{GHz}$  for 0.1 mol % of the additive which is consistent with the report of Nomura.<sup>3</sup> The quality factor is decreased with further increase of the dopant concentration. The ZnO doped samples (0.5 mol %) also have reasonably good quality factors ( $Q_{\mu}xf=124550$  GHz). Among the divalent dopants we studied, the lowest quality factor is found for NiO doped samples as seen from Fig. 2(a).

#### 2. Trivalent dopants

The microwave dielectric properties of BMT dielectrics doped with dopants with oxidation state of 3 are found to be comparatively poor as shown in Fig. 2(b). This is attributed to the formation of lossy secondary phases. The dielectric constant of Bi and Nd doped ceramics show higher values, which can be attributed to the high dielectric polarizabilities (6.12 and 6.15, respectively) of these cations. It is worthwhile to note that if the trivalent dopant's ionic polarizability is lower than the average polarizability (=3.693) (Ref. 29) of the B-site cation in BMT, then the measured dielectric constant decreases. The temperature coefficient of resonant frequencies of BMT as a function of trivalent dopant is given in Fig. 2(b). Except for  $Al_2O_3$  and  $Ga_2O_3$ , the doped samples show high positive  $\tau_f$  values. In Ga and Al doping,  $\tau_f$  approaches negative values, which can be due to the formation of secondary phase such as BaGa<sub>12</sub>O<sub>19</sub> and Ba<sub>10</sub>Al<sub>2</sub>O<sub>13</sub>, respectively. For other dopants such as Fe<sub>2</sub>O<sub>3</sub>, Al<sub>2</sub>O<sub>3</sub>, In<sub>2</sub>O<sub>3</sub>, and Nd<sub>2</sub>O<sub>3</sub>, high positive values of  $\tau_f$  are observed. In general, the quality factor is poor for BMT doped with trivalent additives.

# 3. Tetravalent dopants

The dielectric properties of tetravalent dopant added BMT measured at microwave frequency are plotted in Fig. 2(c). The  $\varepsilon_r$  of all doped BMT samples are increased as compared for pure BMT, except for SnO<sub>2</sub> addition. Though the dielectric polarizability<sup>29</sup> of Zr (3.25) is more than that of Ti (2.93), the dielectric constant of samples doped with



FIG. 2. (a) Variation of dielectric properties of BMT with the addition of divalent dopant. (b) Variation of the microwave dielectric properties of BMT with trivalent dopant addition. (c) Variation of the microwave dielectric properties of BMT with the addition of tetravalent dopant. (d) Variation of the microwave dielectric properties of BMT with the addition of pentavalent dopant. (e) Variation of the microwave dielectric properties of BMT with the addition of pentavalent dopant. (e) Variation of the microwave dielectric properties of BMT with the addition of pentavalent dopant. (e) Variation of the microwave dielectric properties of BMT with the addition of pentavalent dopant. (e) Variation of the microwave dielectric properties of BMT with the addition of pentavalent dopant.

5 mol % TiO<sub>2</sub> has higher values ( $\varepsilon_r$ =27.5) than that doped with an identical concentration of ZrO<sub>2</sub> (25.8). The increase in dielectric constant is believed to be of lattice distortion of

the perovskite structure due to the substitution of tetravalent cation dopant. In a previous report, Lan *et al.*<sup>30</sup> also observed a small enhancement of dielectric constant of BMT with Zr

Downloaded 16 Nov 2005 to 210.212.236.73. Redistribution subject to AIP license or copyright, see http://jap.aip.org/jap/copyright.jsp

doping. It is worthwhile to note that on titania doping in BMT, a ferroelectric BaTiO<sub>3</sub> is formed which is reported<sup>31</sup> to have very high dielectric constant (4000–10000). The present investigation indicates that secondary phases formed during higher percentage of doping have more influence on the dielectric constant, than the individual ionic polarizabilities of the dopants. The addition of  $SnO_2$  and  $CeO_{2-\delta}$  on BMT decreases the  $\tau_f$  to negative values. This observation is consistent with a previous observation by Matsumoto et al.<sup>4</sup> who noted that, apart from improving quality factor, the  $\tau_f$  of BMT decreases to negative values on doping with BaSnO<sub>3</sub>. The titania and hafnia doping increase the  $\tau_f$  of BMT dielectric due to the greater lattice distortion imparted in the disordered perovskite. For 1 mol % of ZrO<sub>2</sub> dopant the  $\tau_f$  value of BMT decreases to 4.5 ppm/°C and then increases to 13 ppm/°C on further addition of the dopant. The  $Q_{\mu}xf$ reaches its maximum value (162 500 GHz) for 0.5 mol % of  $ZrO_2$  dopant where the order parameter is 0.500 (see Table I). For higher concentration of the dopant, the Q factor decreases where the cation ordering is also poor. The microwave quality factor of BMT doped with Ti, Hf, and Ce are poor. On the other hand 0.5 mol % of SnO<sub>2</sub> improved the quality factor of BMT from its undoped quality factorfrequency product of 100 500-122 500 GHz.

# 4. Pentavalent dopants

The effect of pentavalent dopant addition on the microwave dielectric properties of BMT is plotted in Fig. 2(d). It is well known that all the three additives used in this investigation (Sb<sub>2</sub>O<sub>3</sub>, V<sub>2</sub>O<sub>5</sub>, and Nb<sub>2</sub>O<sub>5</sub>) are low melting and can aid liquid phase sintering. The partial substitution of Sb at Ta site has been beneficial in increasing the dielectric constants of the doped samples with Sb<sub>2</sub>O<sub>3</sub> addition. On the other hand the measured dielectric constant decreases with increasing  $V_2O_5$  concentration. This is due to the substitution of a less polarizable V ion (polarizability=2.92) (Ref. 29) at Ta site (polarizability=4.73). The dielectric constant of BMT samples decreases slightly with Nb2O5 addition, which is consistent with a previous observation.<sup>32</sup> The  $\tau_f$  increases monotonously with increase in the V<sub>2</sub>O<sub>5</sub> and Nb<sub>2</sub>O<sub>5</sub> content. The  $\tau_f$  values are 3.1 and 4.9 ppm/°C when BMT is doped with 0.1 and 0.5 mol % of Sb<sub>2</sub>O<sub>3</sub> additive. The quality factor of BMT doped with 0.1 mol % of Sb<sub>2</sub>O<sub>3</sub> is found to be the best ( $Q_{\mu}xf=172500$  GHz) among all the dopants we studied. It is worthwhile to note that the cation ordering is larger for samples doped with  $Sb_2O_3$ . For other dopants  $V_2O_5$  and Nb<sub>2</sub>O<sub>5</sub>, the loss factor increases with dopant concentration. The lowering of Q with  $V_2O_5$  addition disagrees with a recent observation by Huang et al.<sup>12</sup> who observed an enhancement of the quality factor with  $V_2O_5$  incorporation due to the liquid phase sintering.

# 5. Hexavalent dopants

The microwave dielectric properties of the BMT ceramics doped with MoO<sub>3</sub> and WO<sub>3</sub> are also given in Fig. 2(d). For 0.1 mol % of MoO<sub>3</sub> additive the  $\varepsilon_r$  increases from 24.4 to 25.17 and then decreases on further addition. On the other hand the dielectric constant steadily increases to 25.7 up to



FIG. 3. Plot of ionic radius of the dopant vs quality factor of BMT ceramic.

 $2 \mod \%$  of the WO<sub>3</sub> additives and then decreases which may be due to the formation of BaWO<sub>4</sub> [also see Fig. 1 (W)]. The  $\tau_f$  of 0.5 mol % WO<sub>3</sub> doped sample improved to 4.1 from 8 ppm/°C and then increases with further increase in dopant concentration. But the variation of  $\tau_f$  with MoO<sub>3</sub> doping shows an irregular trend, which is believed to be due to the effect of BaMoO<sub>4</sub> secondary phase. The ionic radii of  $W^{6+}$ , Ta<sup>5+</sup>, and Mg<sup>2+</sup> with a coordination number of 6 are 0.58, 0.64, and 0.72 Å, respectively. A partial substitution of W<sup>6+</sup> at Ta<sup>5+</sup> site in BMT not only bring about a charge difference of 4 between Mg<sup>2+</sup> [B' ion in Ba( $B'_{1/3}B''_{2/3}$ )O<sub>3</sub>] and  $W^{6+}$  (B" ion), but the ionic radius difference<sup>23</sup> also increases from 0.08 to 0.14 Å. Furthermore, this substitution compensate for the defects appeared in the crystal as O<sup>2-</sup> ion vacancies. The quality factor frequency product of 0.5 mol % WO<sub>3</sub> doped BMT is 144 500 GHz. The quality factor MoO<sub>3</sub> doped samples are in general poor due to the lossy effects of the secondary phase formed during doping.

Based on the results and discussions made above, we explored a possible relationship between ionic radius of the dopant and the quality factor of BMT samples added with different dopants. The average ionic radius (IR) of *B*-site cation of BMT (i.e.,  $Mg_{1/3}Ta_{2/3}$ ) is calculated as 0.653 Å. A plot of the unloaded quality factor of BMT ceramic doped with 0.1 mol % of the dopants as a function of ionic radius of the dopants is given in Fig. 3. In general when the ionic radii of the dopants are between 0.6 and 0.7 Å (i.e., close to the average ionic radii of the *B*-site ion in BMT) the quality factor reaches maximum values. However, cations such as Ga (IR=0.64 Å), Nb (IR=0.64 Å), and Fe (IR=0.645 Å) (Ref. 23) are not favorable for improving the properties of BMT.

#### 6. Dielectric properties at cryogenic temperatures

Figure 4 represents the variation of quality factor of pure and doped and annealed BMT in the temperature range of 19 to 292 K. The undoped BMT used in this study was not annealed. Here the dielectric loss of unannealed BMT increases with the decrease of temperature due to the presence of paramagnetic defects.<sup>33</sup> In addition to this, it is possible that unannealed BMT may contain considerable amount of point defects such as oxygen vacancies<sup>34</sup> which also decrease



FIG. 4. Variation of unloaded quality factor of pure and doped BMT at cryogenic temperature.

the quality factor at subzero temperatures. Doping with oxygen supplier such as MnO and  $Sb_2O_3$  annihilates the oxygen vacancies in the crystal and annealing increases the cation ordering in the crystal lattice of BMT. These combined effect of these two phenomena resulted in the increase of microwave quality factor on cooling, however, the quality factor of all the samples decreased below 50 K. The quality factor of other doped BMT samples decreases as the temperature of the sample is decreased (see Fig. 4). This can be due to the presence of paramagnetic defects.

## **IV. CONCLUSIONS**

The structural and microwave dielectric property modifications in BMT as a result of doping with several inorganic oxides are investigated. With the addition of dopants the optimized sintering temperature was reduced to 1625 °C. The microwave dielectric properties of pure BMT ceramic sintered at 1625 and annealed at 1450 °C for 40 h are  $\varepsilon_r$ =24.4,  $Q_{\mu}xf$ =100 500 GHz, and  $\tau_f$ =8 ppm/°C. With the addition of 0.1 mol % of the divalent dopant MnO, the dielectric properties of BMT were increased to  $\varepsilon_r = 26.72$ ,  $Q_{\mu}xf=162\ 800\ \text{GHz}$ , and  $\tau_f=6.3\ \text{ppm}/^{\circ}\text{C}$ . The addition of tetravalent dopants leads to noticeable influence on the cation ordering of BMT ceramics. The cation ordering is poor (0.500) for BMT added with 0.5 mol % of  $ZrO_2$  but the dielectric properties are appreciably higher ( $\varepsilon_r$ =25.29,  $Q_{\mu}xf$ =162 500 GHz, and  $\tau_f$ =4.5 ppm/°C). The densification and dielectric properties of BMT are reaching their maximum values with Sb<sub>2</sub>O<sub>3</sub> addition. The microwave dielectric properties of BMT when doped with 0.1 mol of Sb<sub>2</sub>O<sub>3</sub> are given as  $\varepsilon_r = 24.78$ ,  $Q_u x f = 172500$  GHz, and  $\tau_f = 3.1$  ppm/°C. The addition of hexavalent dopants imparts better ordering in BMT due to the greater charge difference between B-site cation. The microwave dielectric properties of BMT doped with 0.5 mol % of WO<sub>3</sub> are  $\varepsilon_r$ =24.9,  $Q_u x f$ =144 500 GHz, and  $\tau_f = 4.1 \text{ ppm/}^{\circ}\text{C}$ .

The microwave quality factor of the doped BMT ceramics shows a proportionate dependence on the ordering of *B*-site cations except for tetravalent dopants. For tetravalent dopants such as  $ZrO_2$ , the high quality factor is observed even for samples with a lower-order parameter. The average ionic radius of *B*-site cation of BMT (i.e.,  $Mg_{1/3}Ta_{2/3}$ ) is calculated as 0.653 Å. It is observed that when the ionic radii of the dopants are between 0.6 and 0.7 Å (i.e., close to the average ionic radii of the *B*-site ion in BMT) the quality factor reaches the maximum.

The quality factor of as-sintered pure BMT decreases when the sample is cooled below 0 °C. On the other hand when  $\text{Sb}^{5+}$  and  $\text{Mn}^{2+}$  doped and annealed BMT the *Q* factor increases on cooling.

# ACKNOWLEDGMENTS

The authors (K.P.S. and M.T.S.) acknowledge Defense Research Development Organization, New Delhi, for financial Support and the other author (M.V.J.) acknowledges the Australian Research Fellowship and the financial support provided under the JCU ARC Discovery Project No. 0449996. The authors are grateful to Dr. U. Syama Prasad and P. Guruswamy for recording powder-diffraction patterns.

- <sup>2</sup>S. Katayama, I. Yoshinaga, N. Yamada, and T. Nagai, J. Am. Ceram. Soc. 79, 2059 (1996).
- <sup>3</sup>S. Nomura, Ferroelectrics **49**, 61 (1983).
- <sup>4</sup>H. Matsumoto, H. Tamura, and K. Wakino, Jpn. J. Appl. Phys., Part 1 **30**, 2347 (1991).
- <sup>5</sup>K. H. Yoon, D. P. King, and E. S. Kim, J. Am. Ceram. Soc. **77**, 1062 (1994).
- <sup>6</sup>E. S. Kim and K. H. Yoon, J. Mater. Sci. **29**, 830 (1994).
- <sup>7</sup>X. M. Chen and Y. J. Wu, J. Mater. Sci.: Mater. Electron. 7, 369 (1996).
  <sup>8</sup>L. Chai, M. A. Akbas, P. K. Davies, and J. Parise, Mater. Res. Bull. 32, 1261 (1997).
- <sup>9</sup>L. Chai and P. K. Davies, Mater. Res. Bull. 33, 1283 (1998).
- <sup>10</sup>H. M. Shirey, M.S. thesis, University of Pittsburg, 2003.
- <sup>11</sup>M.-H. Liang, C.-T. Hu, C.-G. Chiou, H.-Y. Chang, and I.-N. Lin, Ferroelectrics **231**, 691 (1999).
- <sup>12</sup>C.-L. Huang, K.-H. Chiang, and S.-C. Chuang, Mater. Res. Bull. (in press).
- <sup>13</sup>K. P. Surendran, P. Mohanan, and M. T. Sebastian, J. Solid State Chem. **177**, 4031 (2004).
- <sup>14</sup>K. P. Surendran, P. Mohanan, A. Dias, R. L. Moreira, and M. T. Sebastian, Chem. Mater. **17**, 142 (2005).
- <sup>15</sup>T. V. Kolodiazhnyi, A. Petric, G. P. Johari, and A. G. Belous, J. Eur. Ceram. Soc. 22, 2013 (2002).
- <sup>16</sup>S. Janaswamy, G. Sreenivasa Murthy, E. D. Dias, and V. R. K. Murthy, Mater. Lett. 55, 414 (2002).
- <sup>17</sup>M. W. Lufaso, Chem. Mater. **16**, 2148 (2004).
- <sup>18</sup>B. W. Hakki and P. D. Coleman, IRE Trans. Microwave Theory Tech. 8, 402 (1960).
- <sup>19</sup>W. E. Courtney, IEEE Trans. Microwave Theory Tech. 18, 476 (1970).
- <sup>20</sup>K. Leong and J. Mazierska, IEEE Trans. Microwave Theory Tech. 50, 2115 (2002).
- <sup>21</sup>M. V. Jacob, J. Mazierska, K. Leong, and J. Krupka, IEEE Trans. Microwave Theory Tech. **49**, 2401 (2001).
- <sup>22</sup>J. Youn, K. S. Hong, and H. Kim, J. Mater. Res. **12**, 589 (1997).
- <sup>23</sup>R. D. Shannon, Acta Crystallogr., Sect. A: Cryst. Phys., Diffr., Theor. Gen. Crystallogr. A32, 751 (1976).
- <sup>24</sup>Y. K. Kim, K. M. Lee, and H. M. Jang, J. Mater. Sci. 35, 4885 (2000).
- <sup>25</sup>F. S. Galasso, *Perovskites and High Tc. Superconductors* (Gordon and Breach Scientific, New York, 1990).
- <sup>26</sup>J. J. Lander, in *Phase Diagram for Ceramics*, edited by E. M. Levin, C. R. Robbins, H. F. Mc Murdie, and M. K. Reser, (American Ceramic Society, Westerville, Ohio, 1975), p. 118.
- <sup>27</sup>P. K. Davies, Ceram. Trans. **53**, 137 (1995).
- <sup>28</sup>M. K. Lee, J. H. Chung, K. W. Ryu, and Y. H. Lee, *Proceedings of the 30th International Symposium on Electrical Insulating Materials*, Toyohashi, Japan, 27–30 Sept. 1998 (unpublished).
- <sup>29</sup>R. D. Shannon, J. Appl. Phys. **73**, 348 (1993).

<sup>&</sup>lt;sup>1</sup>S. Nomura, K. Toyama, and K. Kaneta, Jpn. J. Appl. Phys., Part 2 21, L624 (1982).

094114-9 Surendran et al.

- <sup>30</sup>W.-A. Lan, M.-H. Liang, C.-T. Hu, K.-S. Liu, and I.-N. Lin, Mater. Chem. Phys. 79, 266 (2003).
- <sup>31</sup>J. P. Grigas, *Microwave Dielectric Spectroscopy of Ferroelectrics and Re*lated Materials: Ferroelectricity & Related Phenomena (Taylor & Francis, New Jersey, 1996).
- <sup>32</sup>M. Thirumal, G. S. Murugan, K. B. R. Varma, and A. K. Ganguli, Mater. Res. Bull. 35, 2423 (2000).
- <sup>33</sup>S. R. Stein, *Proceedings of the 29th Annual Frequency Control Symposium* (Electronic Industries Association, Washington, DC, USA, 1975), p. 321. <sup>34</sup>K. Wakino and H. Tamura, Ceram. Trans. **15**, 305 (1990).